

TRANSLATION**PATENT COOPERATION TREATY****PCT****INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY**
(Chapter II of the Patent Cooperation Treaty)

(PCT Article 36 and Rule 70)

Applicant's or agent's file reference 04S0800P	FOR FURTHER ACTION	See Form PCT/IPEA/416
International application No. PCT/JP2004/012953	International filing date (day/month/year) 06.09.2004	Priority date (day/month/year) 08.10.2003
International Patent Classification (IPC) or national classification and IPC G01N1/32, G01N1/28		
Applicant TOKYO ELECTRON LIMITED		

<p>1. This report is the international preliminary examination report, established by this International Preliminary Examining Authority under Article 35 and transmitted to the applicant according to Article 36.</p> <p>2. This REPORT consists of a total of <u>4</u> sheets, including this cover sheet.</p> <p>3. This report is also accompanied by ANNEXES, comprising:</p> <p>a. <input checked="" type="checkbox"/> (sent to the applicant and to the International Bureau) a total of <u>5</u> sheets, as follows:</p> <p><input checked="" type="checkbox"/> sheets of the description, claims and/or drawings which have been amended and are the basis for this report and/or sheets containing rectifications authorized by this Authority (see Rule 70.16 and Section 607 of the Administrative Instructions).</p> <p><input type="checkbox"/> sheets which supersede earlier sheets, but which this Authority considers contain an amendment that goes beyond the disclosure in the international application as filed, as indicated in item 4 of Box No. I and the Supplemental Box.</p> <p>b. <input type="checkbox"/> (sent to the International Bureau only) a total of _____, containing a sequence listing and/or tables related thereto, in computer readable form only, as indicated in the Supplemental Box Relating to Sequence Listing (see Section 802 of the Administrative Instructions).</p>																									
<p>4. This report contains indications relating to the following items:</p> <table><tr><td><input checked="" type="checkbox"/></td><td>Box No. I</td><td>Basis of the report</td></tr><tr><td><input type="checkbox"/></td><td>Box No. II</td><td>Priority</td></tr><tr><td><input type="checkbox"/></td><td>Box No. III</td><td>Non-establishment of opinion with regard to novelty, inventive step and industrial applicability</td></tr><tr><td><input type="checkbox"/></td><td>Box No. IV</td><td>Lack of unity of invention</td></tr><tr><td><input checked="" type="checkbox"/></td><td>Box No. V</td><td>Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement</td></tr><tr><td><input type="checkbox"/></td><td>Box No. VI</td><td>Certain documents cited</td></tr><tr><td><input type="checkbox"/></td><td>Box No. VII</td><td>Certain defects in the international application</td></tr><tr><td><input type="checkbox"/></td><td>Box No. VIII</td><td>Certain observations on the international application</td></tr></table>		<input checked="" type="checkbox"/>	Box No. I	Basis of the report	<input type="checkbox"/>	Box No. II	Priority	<input type="checkbox"/>	Box No. III	Non-establishment of opinion with regard to novelty, inventive step and industrial applicability	<input type="checkbox"/>	Box No. IV	Lack of unity of invention	<input checked="" type="checkbox"/>	Box No. V	Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement	<input type="checkbox"/>	Box No. VI	Certain documents cited	<input type="checkbox"/>	Box No. VII	Certain defects in the international application	<input type="checkbox"/>	Box No. VIII	Certain observations on the international application
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Date of submission of the demand	Date of completion of this report																								
Name and mailing address of the IPEA/JP	Authorized officer																								
Facsimile No.	Telephone No.																								

INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

International application No.

PCT/JP2004/012953

Box No. I Basis of the report

1. With regard to the language, this report is based on the international application in the language in which it was filed, unless otherwise indicated under this item.

☐ This report is based on translations from the original language into the following language _____, which is the language of a translation furnished for the purposes of:

- ☐ international search (Rule 12.3 and 23.1(b))
☐ publication of the international application (Rule 12.4)
☐ international preliminary examination (Rule 55.2 and/or 55.3)

2. With regard to the elements of the international application, this report is based on (replacement sheets which have been furnished to the receiving Office in response to an invitation under Article 14 are referred to in this report as "originally filed" and are not annexed to this report):

☐ the international application as originally filed/furnished

☒ the description:

pages 1-14 as originally filed/furnished

pages* _____ received by this Authority on _____

pages* _____ received by this Authority on _____

☒ the claims:

nos. 1-8, 10, 12, 14-18 as originally filed/furnished

nos.* _____ as amended (together with any statement) under Article 19

nos.* 9, 13, 21-23 received by this Authority on 08.03.2005

nos.* _____ received by this Authority on _____

☒ the drawings:

sheets fig. 1-12 as originally filed/furnished

sheets* _____ received by this Authority on _____

sheets* _____ received by this Authority on _____

☐ a sequence listing and/or any related table(s) – see Supplemental Box Relating to Sequence Listing.

3. ☒ The amendments have resulted in the cancellation of:

☐ the description, pages _____

☒ the claims, nos. 11, 19, 20

☐ the drawings, sheets/figs _____

☐ the sequence listing (specify): _____

☐ any table(s) related to sequence listing (specify): _____

4. ☐ This report has been established as if (some of) the amendments annexed to this report and listed below had not been made, since they have been considered to go beyond the disclosure as filed, as indicated in the Supplemental Box (Rule 70.2(c)).

☐ the description, pages _____

☐ the claims, nos. _____

☐ the drawings, sheets/figs _____

☐ the sequence listing (specify): _____

☐ any table(s) related to sequence listing (specify): _____

* If item 4 applies, some or all of those sheets may be marked "superseded."

INTERNATIONAL PRELIMINARY REPORT ON PATENTABILITY

International application No.

PCT/JP2004/012953

Box No. V

Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability;
citations and explanations supporting such statement

1. Statement

Novelty (N)	Claims	1-10, 12-18, 21-23	YES
	Claims		NO
Inventive step (IS)	Claims	1-10, 12-18, 21-23	YES
	Claims		NO
Industrial applicability (IA)	Claims	1-10, 12-18, 21-23	YES
	Claims		NO

2. Citations and explanations (Rule 70.7)

Document 1: JP 2003-202278 A (Toshiba Corp.), 18 July
2003

Document 2: JP 2003-522708 A (Tokyo Electron Ltd.), 29
July 2003 & EP 1261761 A

Document 3: JP 2001-223251 A (Tokyo Electron Ltd.), 17
August 2001

Claims 1 to 10, 12 to 18 and 21 to 23

Document 1 (in particular, refer to the drawings and paragraphs [0009], [0020] and [0023]) discloses a processing device for degrading sample materials which is suitable for carrying out an analysis of the impurities within any prescribed region of a sample material, said processing device being equipped with a substantially cylindrical pressing member that is capable of pressing upon the surface of the sample material to be processed in order to drip and then retain a solution upon the surface of said sample material. Therein, document 1 further indicates that the constituent members of the processing device are configured from a polytetrafluoroethylene resin.

Meanwhile, documents 2 and 3 disclose methods for assaying the impurities within the quartz member that is

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Box No. V	Reasoned statement under Article 35(2) with regard to novelty, inventive step or industrial applicability; citations and explanations supporting such statement
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employed during the processing of a semiconductor wafer, wherein a processing solution that comprises an etching solution is dripped and then retained upon the sample material so that the impurities from the sample material dissolve into the etching solution, whereafter the metals within the impurity-containing etching solution are assayed by means of inductively coupled plasma mass spectrometry or the like. Furthermore, documents 2 and 3 also indicate that it is possible to adjust the processing period and the processing conditions so as to achieve a target etching depth.

However, the feature wherein the inspection assisting device, which is used when the processing solution is applied to the targeted section of the rod-like quartz member in the semiconductor treatment apparatus, is configured from end plates that engage with the recessed parts of the rod-like members, a frame that connects said end plates and a liquid receiving part that is formed between the end plates is not disclosed in any of the documents that are cited in the international search report, and would not have been obvious to a person skilled in the art.

In addition, the annular member that is used when the processing solution is applied to the targeted section of the rod-like quartz member in the semiconductor treatment apparatus, wherein a seal member is provided to the bottom surface of the annular member and an embedded magnet is further provided thereto, is not disclosed in any of the documents that are cited in the international search report, and would not have been obvious to a person skilled in the art.